

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/701,332)	
)	
Filed:	November 4, 2003)	Conf. No.: 5874
)	
Title:	A Novel BISR Mode to Test the Redundant Elements and Regular Functional Memory to Avoid Test Escapes)	
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Inventor:	Ghasi R. Agrawal et al.)	
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Art Unit:	2117)	
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Examiner:	Steve N. Nguyen)	
)	
Atty. Ref:	03-1343)	

RESPONSE TO THE OFFICE ACTION MAILED APRIL 11, 2008

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed April 11, 2008, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.